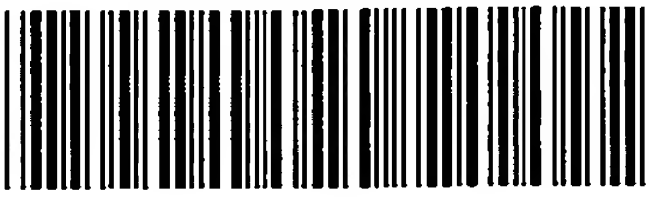


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/625,792	MANDRO ET AL.	
	Examiner	Art Unit	
	Patrick J. Lee	2878	

SEARCHED			
Class	Subclass	Date	Examiner
250	221, 222.1, 231.1, 231.13	12/23/2005	PL
250	231.14	12/23/2005	PL
250	231.18	12/23/2005	PL
341	13, 141	12/23/2006	PL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (See attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	12/23/2005	PL